Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/541,015	SCHLEUCHER, HEIKO	
Examiner	Art Unit	
SANG KIM	3654	

					
SEARCHED					
Class	Subclass	Date	Examiner		
242	580 579 402 172	8/21/2007	SK		
24	600.9	8/21/2007	SK ,		
24	601.24	8/21/2007	SK		
24	601.79	8/21/2007	SK		
24	698.13	8/21/2007	SK		
742	584.1	12-18-07	SK		
242	587.1	12-18-07	SK		
updated	×	12-18-07	SIC		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
updated	Х	12-18-07	SK	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
John Nguyen: 242/402, 172 Dean Kramer: 294/No search	8/14/2007	SK		
James Brittain: 24/600.9, 601.24, 601.79, 698.13	8/21/2007	sĸ		
Scott Hurghand: 242/584.1,587.1	12-18-67	su		
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